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Erratum

$\mu {\rm SR}$ evidence of low frequency spin fluctuations in the AF phase of hole-doped NiO

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Some mistakes have been found in Section 3. Although they are not crucial in the present paper, they could be relevant for a throughout study of the decay laws in disordered systems.

At line 15, column 2, p. 221 one should read: "For $f(\lambda) \equiv \delta(\lambda - \lambda_{\mu})$ one has clearly a simple exponential decay $(\beta = 1 \text{ in Eq. } (2))$, while for $f(\lambda) \equiv (\sqrt{\lambda_{\mu}}/2\sqrt{\pi\lambda^3}) \exp(-\lambda_{\mu}/4\lambda)$ one obtains $P_{\mu}(t) = \exp\left[-(\lambda_{\mu}t)^{1/2}\right]$ ". The parameter λ_{μ} in the formulas above, however, is not in general the average depolarization rate defined by equation (4), as was written in line 20. Therefore, the comparison reported in Figure 3 between the experimental λ_{μ} 's derived with equation (2) and the average rate expressed by equation (5) is not entirely justified from a formal point of view. Nevertheless, one can still describe the temperature dependence of the μ^+ relaxation process in terms of the effective rate λ_{μ} .

The second line of equation (5), p. 222, should be written $\times \exp[-t/\tau(\Delta_i, T)] \exp(-i\omega_\mu t) dt d\Delta_i$.

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